

Scope

50um Al and 70um Cu LMT tapes were thermode soldered to corresponding sites on PP1-W & FP1-N boards, the tapes had a plated gold thickness of 0.2 & 0.4 um (nominal). The objectives of the tests was to show that reducing the gold thickness reduced the amount of gold/tin intermetallic compounds formed and led to stronger joints and also investigate simpler alternatives.

Results

Dwell varied for experiments, all other settings remain constant unless otherwise stated

Test 1 KAPTON/Al/Ni/AU soldered to Cu/SnPb/FR4									
Machine settings: Pre-heat 60°C/2s, Ramp 2s, Dwell Varies, Cool to 60°C, P=4									
Sample No.	Thickness	Nominal Gold	Temperature Dwell	Pressure Dwell	Peel strengths at each tape site on Patch Panels (g)	841	640	739	692
	8 0.2um	300°C	5s	4	997	913	749	1196	1023
1 0.2um	350°C	7.5s	4	1340	1017	904	1192	1073	935
5 0.2um	350°C	10s	4	1418	1137	1268	1360	1057	1342
7 0.2um	350°C								1123
3 0.4um	350°C	5s	4	509	690	438	911	401	381
4 0.4um	350°C	7.5s	4	479	524	317	594	373	455
6 0.4um	350°C	10s	4	475	755	530	490	620	368
2 0.4um	300°C	7.5s	4	354	297	271	82	264	440
9 0.4um	300°C	10s	4	267	464	275	292	306	608
									487
									546
									552
									633
									575
									551
									454
									389
									616
									355
									77
									244
									1637
									1725
									1935
									Average 678

Test 2 KAPTON/Cu/Ni/AU soldered to Cu/SnPb/FR4									
Machine settings: Pre-heat 60°C/2s, Ramp 2s, Dwell Varies, Cool to 60°C, P=4									
Sample No.	Thickness	Nominal Gold	Temperature Dwell	Pressure Dwell	Peel strengths at each tape site on Patch Panels (g)	841	640	739	692
10 0.2um	350°C	10s	4	172	129	104	144	100	120
11 0.4um	350°C	10s	4	37	0	30	28	11	36
									31
									36
									37

Test 3 KAPTON/Cu/Ni/SnPb soldered to Cu/SnPb/FR4 (Au stripped with solder, solder cleaned off)									
Machine settings: Pre-heat 60°C/2s, Ramp 2s, Dwell Varies, Cool to 60°C, P=4									
Sample No.	Thickness	Nominal Gold	Temperature Dwell	Pressure Dwell	Peel strengths at each tape site on Patch Panels (g)	841	640	739	692
12 N/A	350°C	10s	4	2427	2329	1203	1719	1867	2272
									1342
									1708
									1288
									1677
									1517
									2104
									1788

Test 4 KAPTON/Cu soldered to Cu/SnPb/FR4									
Machine settings: Pre-heat 60°C/2s, Ramp 2s, Dwell Varies, Cool to 60°C, P=4									
Sample No.	Thickness	Nominal Gold	Temperature Dwell	Pressure Dwell	Peel strengths at each tape site on Patch Panels (g)	841	640	739	692
13	300°C	15	4	675	1186	1121	1382	1117	2591
									3000
									3000
									2365
									2838
									3000
									2106

Test 5 KAPTON/Al/Ni/SnPb soldered to Cu/SnPb/FR4 (Au stripped with solder, solder cleaned off)									
Machine settings: Pre-heat 60°C/2s, Ramp 2s, Dwell Varies, Cool to 60°C, P=4									
Sample No.	Thickness	Nominal Gold	Temperature Dwell	Pressure Dwell	Peel strengths at each tape site on Patch Panels (g)	841	640	739	692
14	Thin gold strip 350°C	10	4	2245	2348	1934	1620	2105	1900
									181
									2298
									1587
									1637
									1725
									1935

Conclusions

Strongest joints are achieved soldering directly to copper or where Al is required Ni plating on Al (see 12 & 13)
 Gold is a problem since to much causes weak joints due to the formation of intermetallic compounds
 Control of gold thickness is obviously difficult for the supplier
 Porous or thin gold allows the Ni to oxidise resulting in very poor joint strengths.

Recommendation

Providing that we are not forming any galvanic cells which could corrode in the presence of moisture we should switch to a SnPb coating over the Cu and Al/Ni.

Recommendation

Repeat with gold coated tapes
Repeat at lower temperature e.g. 280°C

Conclusion

By increasing the preheat temperature and time (180°C/9s) a wide processing window can be used from 350°C/15s (earlier results, no damage to KAPTON) to 240°C/15s, from the lower limits of this boundary time and temperature can be increased until the upper limit is reached. See below-

	350°C	300°C	280°C	260°C	240°C	220°C
	Possible Kaption damage	Tested	Inferred	Inferred	Tested	Tested
30 s	Tested	Tested	Tested	Tested	Probabl	Inferred
15s	Inferred	Tested	Tested	Tested	Probabl	Inferred
10s	Inferred	Tested	Tested	Tested	Probabl	Inferred

Key-	Good	Tested means that there are hard results to back up the settings
	Borderline	Inferred means you can assume the settings work because of tested results above, below or beside
	Poor	

Note the failure mode was at the Al/KAPTON interface, I expected the results to be higher than the earlier samples I stripped the gold from and tinned.

Recommendation
If possible repeat with a larger number of samples

Check whether the adhesion of the Al to KAPTON has been compromised somehow during plating e.g. by higher bath temperatures.